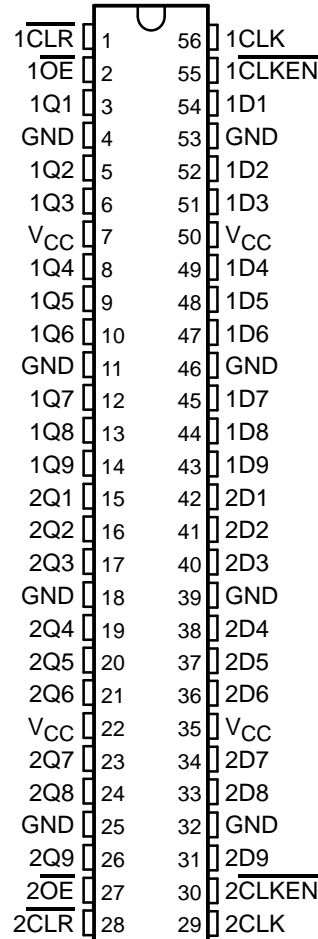


SN54ABT162823A, SN74ABT162823A 18-BIT BUS-INTERFACE FLIP-FLOPS WITH 3-STATE OUTPUTS

SCBS666A – JULY 1996 – REVISED MAY 1997

- **Members of the Texas Instruments Widebus™ Family**
- **Output Ports Have Equivalent 25-Ω Series Resistors So No External Resistors Are Required**
- **State-of-the-Art EPIC-II B™ BiCMOS Design Significantly Reduces Power Dissipation**
- **High-Impedance State During Power Up and Power Down**
- **Typical V_{OLP} (Output Ground Bounce) < 1 V at $V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$**
- **Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise**
- **Flow-Through Architecture Optimizes PCB Layout**
- **Package Options Include Plastic 300-mil Shrink Small-Outline (DL) Package and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings**

SN54ABT162823A . . . WD PACKAGE
SN74ABT162823A . . . DL PACKAGE
(TOP VIEW)



description

These 18-bit bus-interface flip-flops feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing wider buffer registers, I/O ports, bidirectional bus drivers with parity, and working registers.

The 'ABT162823A can be used as two 9-bit flip-flops or one 18-bit flip-flop. With the clock-enable ($\overline{\text{CLKEN}}$) input low, the D-type flip-flops enter data on the low-to-high transitions of the clock. Taking $\overline{\text{CLKEN}}$ high disables the clock buffer, thus latching the outputs. Taking the clear ($\overline{\text{CLR}}$) input low causes the Q outputs to go low independently of the clock.

A buffered output-enable ($\overline{\text{OE}}$) input places the nine outputs in either a normal logic state (high or low level) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components. $\overline{\text{OE}}$ does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The outputs, which are designed to source or sink up to 12 mA, include equivalent 25-Ω series resistors to reduce overshoot and undershoot.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

Widebus and EPIC-II B are trademarks of Texas Instruments Incorporated.

UNLESS OTHERWISE NOTED this document contains PRODUCTION DATA information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS
INSTRUMENTS**

POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

Copyright © 1997, Texas Instruments Incorporated

SN54ABT162823A, SN74ABT162823A

18-BIT BUS-INTERFACE FLIP-FLOPS

WITH 3-STATE OUTPUTS

SCBS666A – JULY 1996 – REVISED MAY 1997

description (continued)

When V_{CC} is between 0 and 2.1 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 2.1 V, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT162823A is characterized for operation over the full military temperature range of -55°C to 125°C . The SN74ABT162823A is characterized for operation from -40°C to 85°C .

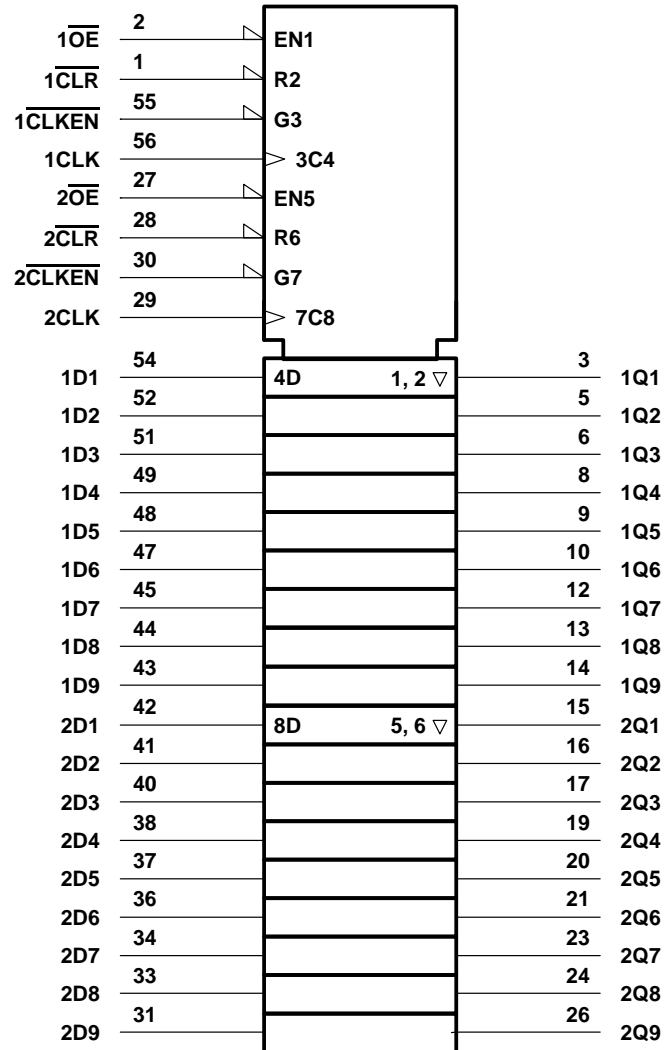
FUNCTION TABLE
(each 9-bit flip-flop)

| INPUTS | | | | | OUTPUT Q |
|-----------------|------------------|--------------------|------------|---|-------------|
| \overline{OE} | \overline{CLR} | \overline{CLKEN} | CLK | D | |
| L | L | X | X | X | L |
| L | H | L | \uparrow | H | H |
| L | H | L | \uparrow | L | L |
| L | H | L | L | X | Q_0 |
| L | H | H | X | X | Q_0 |
| H | X | X | X | X | Z |

SN54ABT162823A, SN74ABT162823A
18-BIT BUS-INTERFACE FLIP-FLOPS
WITH 3-STATE OUTPUTS

SCBS666A – JULY 1996 – REVISED MAY 1997

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

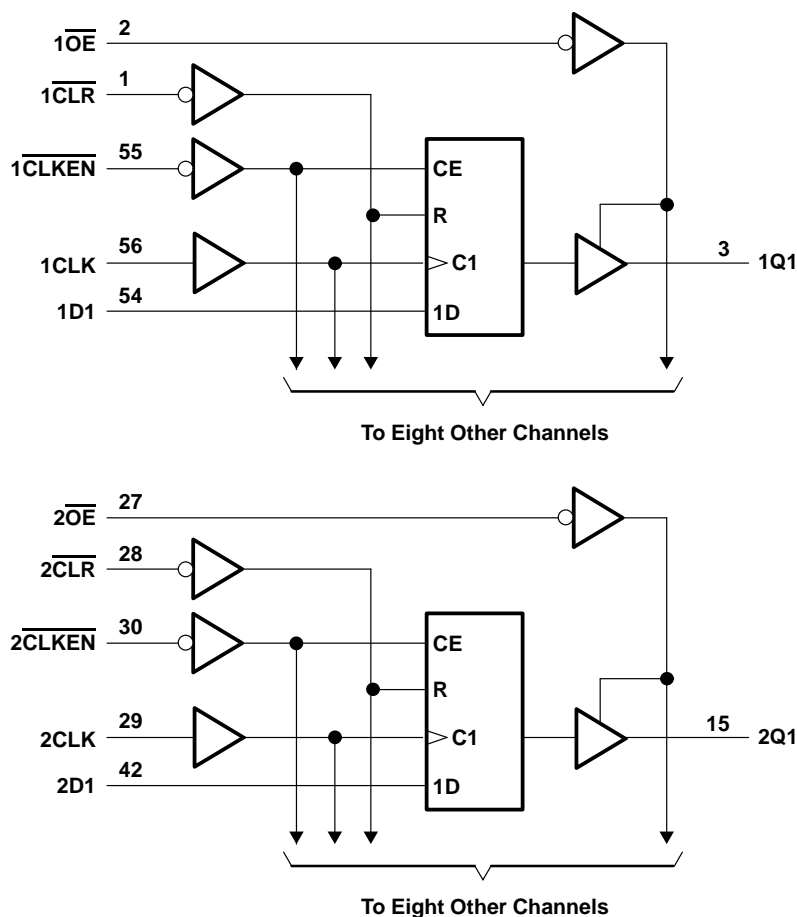
SN54ABT162823A, SN74ABT162823A

18-BIT BUS-INTERFACE FLIP-FLOPS

WITH 3-STATE OUTPUTS

SCBS666A – JULY 1996 – REVISED MAY 1997

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

| | |
|---|-----------------|
| Supply voltage range, V_{CC} | –0.5 V to 7 V |
| Input voltage range, V_I (see Note 1) | –0.5 V to 7 V |
| Voltage range applied to any output in the high or power-off state, V_O | –0.5 V to 5.5 V |
| Current into any output in the low state, I_O | 30 mA |
| Input clamp current, I_{IK} ($V_I < 0$) | –18 mA |
| Output clamp current, I_{OK} ($V_O < 0$) | –50 mA |
| Package thermal impedance, θ_{JA} (see Note 2): DL package | 74°C/W |
| Storage temperature range, T_{stg} | –65°C to 150°C |

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES:
1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
 2. The package thermal impedance is calculated in accordance with JESD 51, except through-hole packages, which use a trace length of zero.

SN54ABT162823A, SN74ABT162823A

18-BIT BUS-INTERFACE FLIP-FLOPS

WITH 3-STATE OUTPUTS

SCBS666A – JULY 1996 – REVISED MAY 1997

recommended operating conditions (see Note 3)

| | | SN54ABT162823A | | SN74ABT162823A | | UNIT |
|---------------------|------------------------------------|-----------------|-----------------|----------------|-----------------|------|
| | | MIN | MAX | MIN | MAX | |
| V _{CC} | Supply voltage | 4.5 | 5.5 | 4.5 | 5.5 | V |
| V _{IH} | High-level input voltage | 2 | | 2 | | V |
| V _{IL} | Low-level input voltage | | 0.8 | | 0.8 | V |
| V _I | Input voltage | 0 | V _{CC} | 0 | V _{CC} | V |
| I _{OH} | High-level output current | | –12 | | –12 | mA |
| I _{OL} | Low-level output current | | 12 | | 12 | mA |
| Δt/Δv | Input transition rise or fall rate | Outputs enabled | | 10 | 10 | ns/V |
| Δt/ΔV _{CC} | Input transition rise or fall rate | 200 | | 200 | | μs/V |
| T _A | Operating free-air temperature | –55 | 125 | –40 | 85 | °C |

NOTE 3: Unused inputs must be held high or low to prevent them floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER | TEST CONDITIONS | | T _A = 25°C | | | SN54ABT162823A | | SN74ABT162823A | | UNIT |
|--------------------|--|--------------------------|-----------------------|------|------|----------------|------|----------------|------|------|
| | | | MIN | TYP† | MAX | MIN | MAX | MIN | MAX | |
| V _{IK} | V _{CC} = 4.5 V, I _I = –18 mA | | | | –1.2 | | –1.2 | | –1.2 | V |
| V _{OH} | V _{CC} = 4.5 V, I _{OH} = –1 mA | | 2.5 | | | 2.5 | | 2.5 | | V |
| | V _{CC} = 5 V, I _{OH} = –1 mA | | 3 | | | 3 | | 3 | | |
| | V _{CC} = 4.5 V | I _{OH} = –3 mA | 2.4 | | | 2.4 | | 2.4 | | |
| | | I _{OH} = –12 mA | 2* | | | | | 2 | | |
| V _{OL} | V _{CC} = 4.5 V | I _{OL} = 8 mA | | 0.4 | 0.8 | | 0.8 | | 0.65 | V |
| | | I _{OL} = 12 mA | | | | | | | 0.8 | |
| I _I | V _{CC} = 5.5 V, V _I = V _{CC} or GND | | | | ±1 | | ±1 | | ±1 | μA |
| I _{OZPU} | V _{CC} = 0 to 2.1 V, V _O = 0.5 V to 2.7 V, \overline{OE} = X | | | | ±50 | | ±50 | | ±50 | μA |
| I _{OZPD} | V _{CC} = 2.1 V to 0, V _O = 0.5 V to 2.7 V, \overline{OE} = X | | | | ±50 | | ±50 | | ±50 | μA |
| I _{OZH} ‡ | V _{CC} = 5.5 V, V _O = 2.7 V | | | | 10 | | 10 | | 10 | μA |
| I _{OZL} ‡ | V _{CC} = 5.5 V, V _O = 0.5 V | | | | –10 | | –10 | | –10 | μA |
| I _{off} | V _{CC} = 0, V _I or V _O ≤ 4.5 V | | | | ±100 | | | | ±100 | μA |
| I _{CEX} | V _{CC} = 5.5 V, V _O = 5.5 V | Outputs high | | | 50 | | 50 | | 50 | μA |
| I _O § | V _{CC} = 5.5 V, V _O = 2.5 V | | –25 | –55 | –100 | –25 | –100 | –25 | –100 | mA |
| I _{CC} | V _{CC} = 5.5 V, I _O = 0, V _I = V _{CC} or GND | Outputs high | | | 0.5 | | 0.5 | | 0.5 | mA |
| | | Outputs low | | | 80 | | 80 | | 80 | |
| | | Outputs disabled | | | 0.5 | | 0.5 | | 0.5 | |
| ΔI _{CC} ¶ | V _{CC} = 5.5 V, One input at 3.4 V, Other inputs at V _{CC} or GND | | | | 1.5 | | 1.5 | | 1.5 | mA |
| C _i | V _I = 2.5 V or 0.5 V | | | 3.5 | | | | | | pF |
| C _o | V _O = 2.5 V or 0.5 V | | | 9 | | | | | | pF |

* On products compliant to MIL-PRF-38535, this parameter does not apply.

† All typical values are at V_{CC} = 5 V.

‡ The parameters I_{OZH} and I_{OZL} include the input leakage current.

§ Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

¶ This is the increase in supply current for each input that is at the specified TTL-voltage level rather than V_{CC} or GND.

PRODUCT PREVIEW information concerns products in the formative or design phase of development. Characteristic data and other specifications are design goals. Texas Instruments reserves the right to change or discontinue these products without notice.



POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

SN54ABT162823A, SN74ABT162823A

18-BIT BUS-INTERFACE FLIP-FLOPS

WITH 3-STATE OUTPUTS

SCBS666A – JULY 1996 – REVISED MAY 1997

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

| | | | V _{CC} = 5 V, T _A = 25°C | | SN54ABT162823A | | SN74ABT162823A | | UNIT |
|--------------------|------------------------|-----------------|---|-----|----------------|-----|----------------|-----|------|
| | | | MIN | MAX | MIN | MAX | MIN | MAX | |
| f _{clock} | Clock frequency | | 0 | 150 | 0 | 150 | 0 | 150 | MHz |
| t _w | Pulse duration | CLR low | 3.3 | | 3.3 | | 3.3 | | ns |
| | | CLK high or low | 3.3 | | 3.3 | | 3.3 | | |
| t _{su} | Setup time before CLK↑ | CLR inactive | 1.6 | | 2 | | 1.6 | | ns |
| | | Data | 2 | | 2 | | 2 | | |
| | | CLKEN low | 2.8 | | 2.8 | | 2.8 | | |
| t _h | Hold time after CLK↑ | Data | 1.2 | | 1.2 | | 1.2 | | ns |
| | | CLKEN low | 0.6 | | 0.6 | | 0.6 | | |

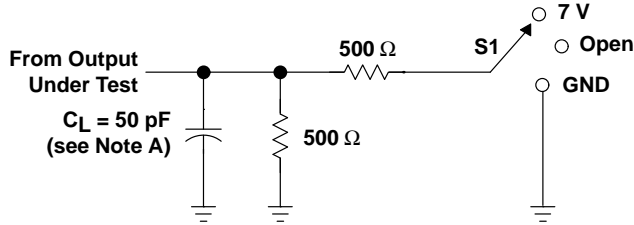
switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

| PARAMETER | FROM (INPUT) | TO (OUTPUT) | V _{CC} = 5 V, T _A = 25°C | | | SN54ABT162823A | | SN74ABT162823A | | UNIT |
|------------------|-----------------|----------------|---|-----|-----|----------------|------|----------------|-----|------|
| | | | MIN | TYP | MAX | MIN | MAX | MIN | MAX | |
| f _{max} | | | 150 | | | 150 | | 150 | | MHz |
| t _{PLH} | CLK | Q | 2.3 | 4.6 | 6.2 | 2.3 | 8.4 | 2.3 | 7.5 | ns |
| t _{PHL} | | | 2.8 | 4.6 | 6.1 | 2.8 | 7.1 | 2.8 | 6.7 | |
| t _{PHL} | CLR | Q | 2.8 | 5 | 6.3 | 2.8 | 7.2 | 2.8 | 7 | ns |
| t _{PZH} | OE | Q | 1.7 | 3.8 | 5 | 1.7 | 5.8 | 1.7 | 5.9 | ns |
| t _{PZL} | | | 3 | 5 | 6.1 | 3 | 7.2 | 3 | 7 | |
| t _{PHZ} | OE | Q | 2.6 | 4.8 | 6.1 | 2.6 | 7.3 | 2.6 | 6.6 | ns |
| t _{PLZ} | | | 1.9 | 4.6 | 6.7 | 1.9 | 10.2 | 1.9 | 9 | |

UNLESS OTHERWISE NOTED this document contains PRODUCTION DATA information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

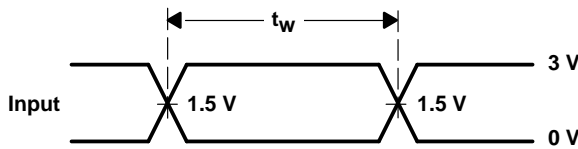


PARAMETER MEASUREMENT INFORMATION

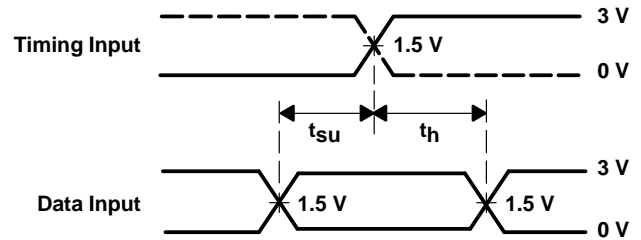


LOAD CIRCUIT

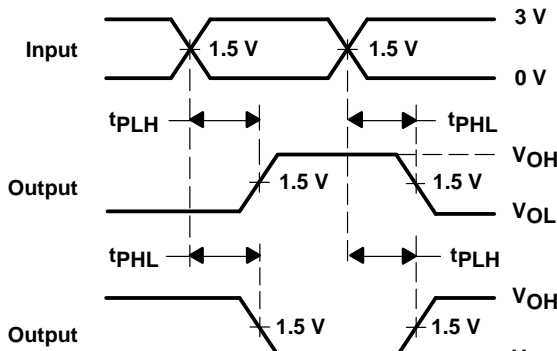
| TEST | S1 |
|-------------------|------|
| t_{PLH}/t_{PHL} | Open |
| t_{PLZ}/t_{PZL} | 7 V |
| t_{PHZ}/t_{PZH} | Open |



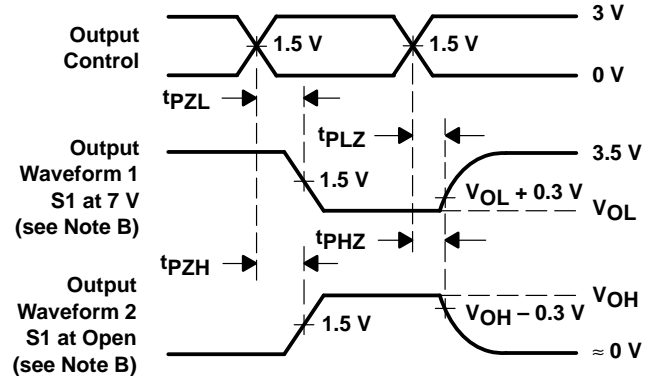
VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10$ MHz, $Z_O = 50 \Omega$, $t_r \leq 2.5$ ns, $t_f \leq 2.5$ ns.
D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

IMPORTANT NOTICE

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.